

TOSHIBA Diode Silicon Epitaxial Planar Type

# 1SS226

## Ultra High Speed Switching Application

- Small package : SC-59
- Low forward voltage :  $V_F(3) = 0.9V$  (typ.)
- Fast reverse recovery time:  $t_{rr} = 1.6ns$  (typ.)
- Small total capacitance :  $C_T = 0.9pF$  (typ.)

## Absolute Maximum Ratings (Ta = 25°C)

| Characteristic                 | Symbol    | Rating  | Unit |
|--------------------------------|-----------|---------|------|
| Maximum (peak) reverse voltage | $V_{RM}$  | 85      | V    |
| Reverse voltage                | $V_R$     | 80      | V    |
| Maximum (peak) forward current | $I_{FM}$  | 300 (*) | mA   |
| Average forward current        | $I_O$     | 100 (*) | mA   |
| Surge current (10ms)           | $I_{FSM}$ | 2 (*)   | A    |
| Power dissipation              | P         | 150     | mW   |
| Junction temperature           | $T_j$     | 125     | °C   |
| Storage temperature range      | $T_{stg}$ | -55~125 | °C   |

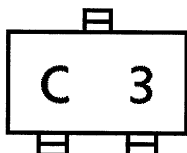
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(\*) Unit rating. Total rating = Unit rating × 0.7.

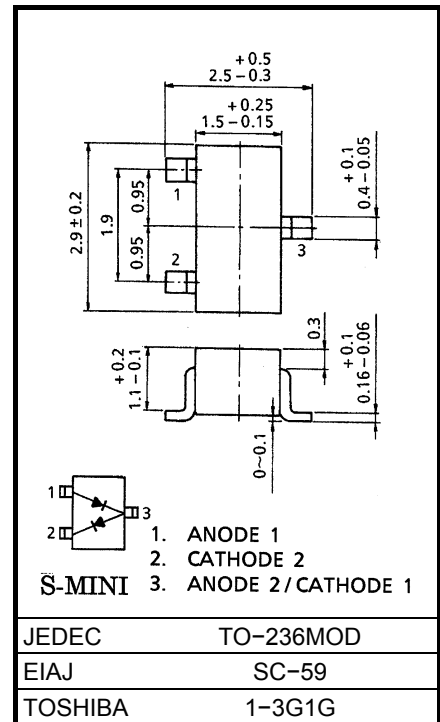
## Electrical Characteristics (Ta = 25°C)

| Characteristic        | Symbol   | Test Circuit | Test Condition       | Min | Typ. | Max  | Unit |
|-----------------------|----------|--------------|----------------------|-----|------|------|------|
| Forward voltage       | $V_F(1)$ | —            | $I_F = 1mA$          | —   | 0.60 | —    | V    |
|                       | $V_F(2)$ | —            | $I_F = 10mA$         | —   | 0.72 | —    |      |
|                       | $V_F(3)$ | —            | $I_F = 100mA$        | —   | 0.90 | 1.20 |      |
| Reverse current       | $I_R(1)$ | —            | $V_R = 30V$          | —   | —    | 0.1  | μA   |
|                       | $I_R(2)$ | —            | $V_R = 80V$          | —   | —    | 0.5  |      |
| Total capacitance     | $C_T$    | —            | $V_R = 0, f = 1MHz$  | —   | 0.9  | 3.0  | pF   |
| Reverse recovery time | $t_{rr}$ | —            | $I_F = 10mA$ (Fig.1) | —   | 1.6  | 4.0  | ns   |

## Marking



Unit: mm



Weight: 0.012g

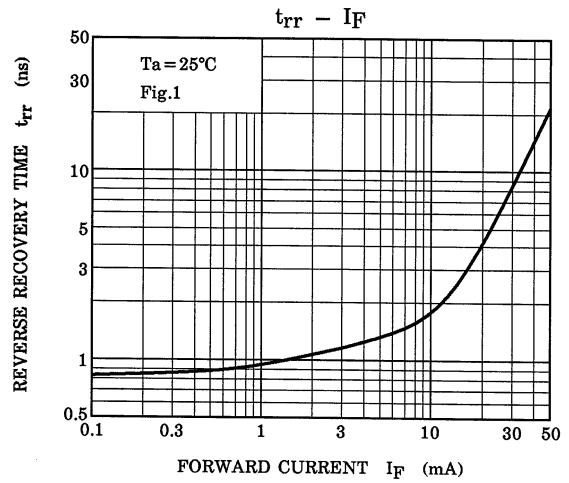
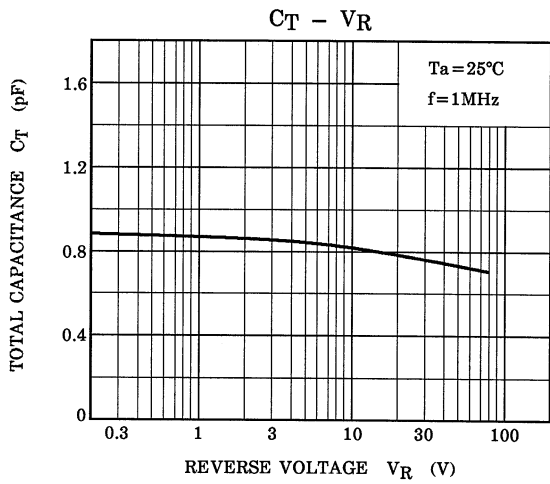
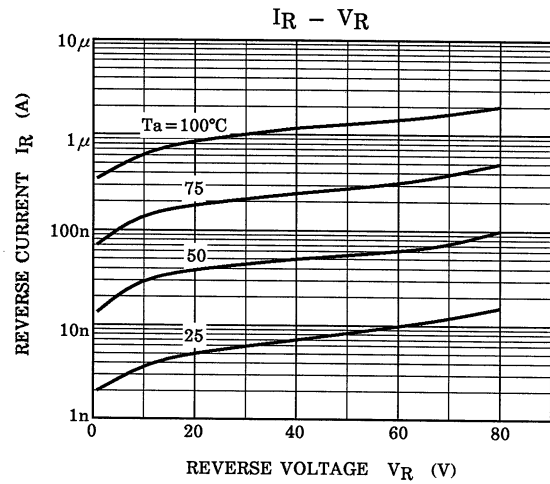
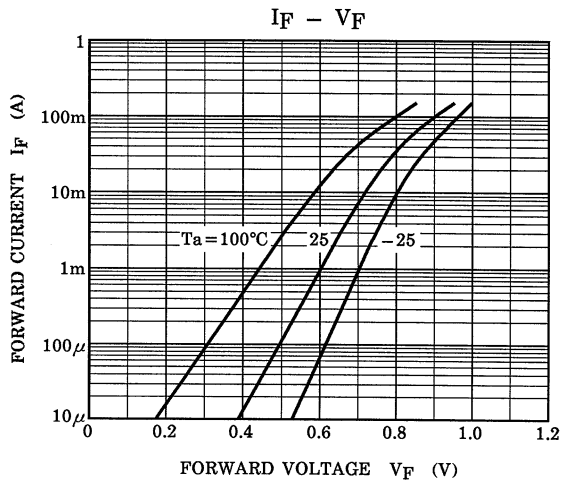
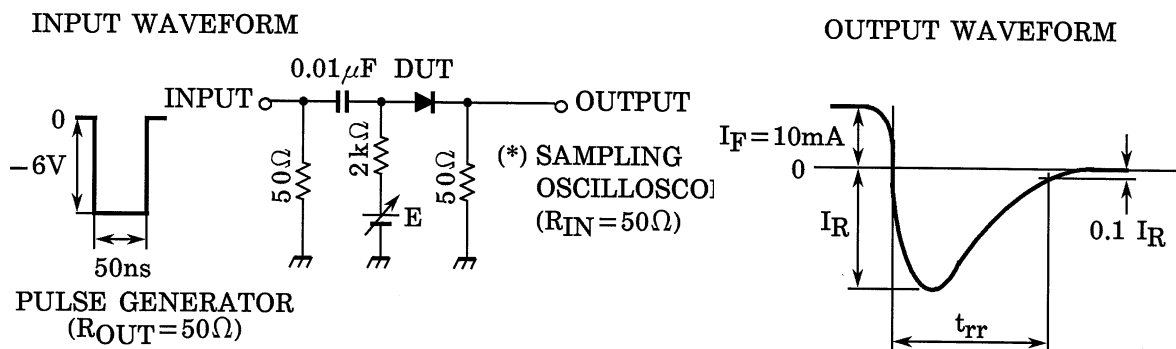


Fig.1 Reverse recovery time ( $t_{rr}$ ) test circuit



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20070701-EN GENERAL

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